

<b>Notice of References Cited</b>	Application/Control No. 10/581,809		Applicant(s)/Patent Under Reexamination HEINLE, FRANK	
	Examiner ISAAK JAMA		Art Unit 4163	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0215003	11-2003	Bottomley et al.	375/148
*	B	US-6,625,197	09-2003	Lundby et al.	375/130
*	C	US-6,813,309	11-2004	Ogino, Tooru	375/148
*	D	US-7,203,220	04-2007	Baltersee et al.	375/145
*	E	US-6,456,611	09-2002	Hu et al.	370/342
*	F	US-7,106,783	09-2006	Seo et al.	375/148
*	G	US-6,459,883	10-2002	Subramanian et al.	455/67.11
*	H	US-6,175,588	01-2001	Visotsky et al.	375/148
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.